

ABSTRACT

A terminal of IC test fixture comprising a body, a spring contact arm and a soldering portion and there are at least one hollow holes on the body of the terminal. During testing, the electronic charges flow on the terminals generate electromagnetic field at the direction perpendicular to the electrical current flow, and the electronic current flows, which are near, generates electromagnetic fields with different directions, by the compensation and interference of electromagnetic fields each other, making the electromagnetic interference reduced. To suppress the electronic interference, the aforesaid hollow holes subdivide said electronic current flow, and that helps to constrain the electromagnetic interference during testing. Therefore, this invention can minimize electromagnetic interference among terminals for higher efficiency in testing the high frequency transmission IC's.